

**Search Notes**

Application/Control No.

10/785,259

Examiner

B. Chen

Applicant(s)/Patent under  
Reexamination

OHKAWA ET AL.

Art Unit

1762

**SEARCHED**

Class	Subclass	Date	Examiner
updated	previous	11/6/2006	BC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
427	255.29	11/6/2006	BC
427	255.31	11/6/2006	BC
427	376.2	11/6/2006	BC

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	11/6/2006	BC